

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination WU, CHIH-HENG	
		Examiner Paulos M. Natnael	Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,927,801	08-2005	Yugami et al.	348/458
*	B	US-6,144,410	11-2000	Kikuchi et al.	348/441
*	C	US-4,807,031	02-1989	Broughton et al.	348/460
*	D	US-6,504,577	01-2003	Voltz et al.	348/448
*	E	US-6,330,032	12-2001	Boehlke, Kenneth A.	348/452
*	F	US-6,501,507	12-2002	Canfield, Barth Alan	348/441
*	G	US-5,161,014	11-1992	Pearson et al.	348/443
*	H	US-5,274,447	12-1993	Nakagaki et al.	348/443
*	I	US-5,488,389	01-1996	Nakanishi et al.	345/670
*	J	US-5,329,309	07-1994	Dorricott et al.	348/97
*	K	US-6,873,368	03-2005	Yu et al.	348/441
*	L	US-5,610,661	03-1997	Bhatt, Bhavesh B.	348/446
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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